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(12) **United States Design Patent**
Sekiguchi et al.

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(54) **REFRACTOMETER**

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(**) Term: **14 Years**

(21) Appl. No.: **29/305,949**

(22) Filed: **Mar. 31, 2008**

(51) **LOC (9) Cl.** **10-04**

(52) **U.S. Cl.** **D10/78**

(58) **Field of Classification Search** D10/78;
356/128-137, 243.1, 246

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

2,383,347 A * 8/1945 Silge 356/135

2,633,053 A * 3/1953 Hansen 356/135

D554,549 S * 11/2007 Amamiya et al. D10/78

7,369,221 B2 * 5/2008 Amamiya et al. 356/135

* cited by examiner

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Ltd.

(57) **CLAIM**

The ornamental design for a refractometer, as substantially
shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of our new design for a
refractometer;

FIG. 2 is a left side elevation view thereof;

FIG. 3 is right side elevation view thereof;

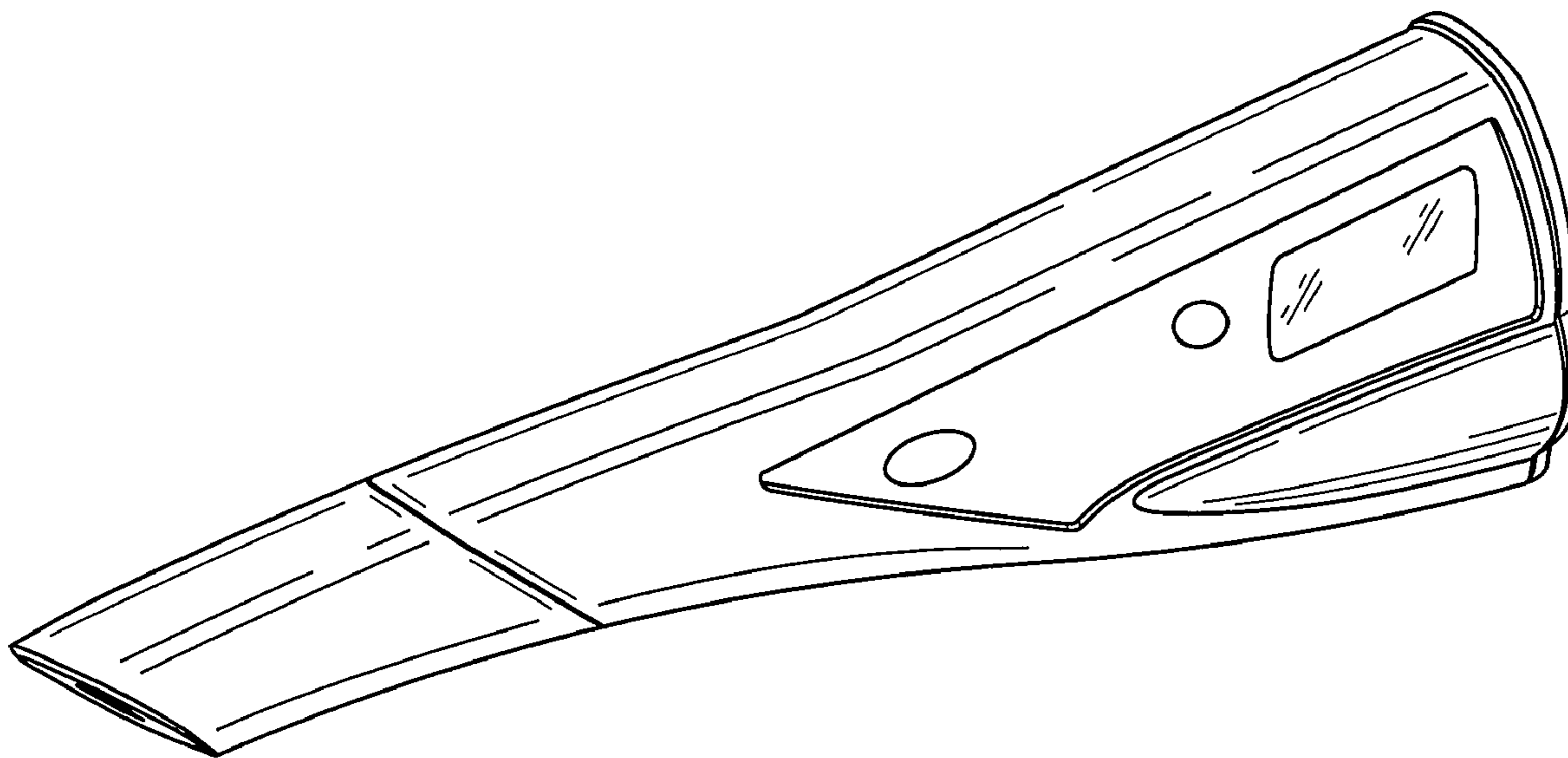
FIG. 4 is a back side elevation view thereof;

FIG. 5 is a front side elevation view thereof;

FIG. 6 is a top plan view thereof; and,

FIG. 7 is a bottom view thereof.

1 Claim, 2 Drawing Sheets



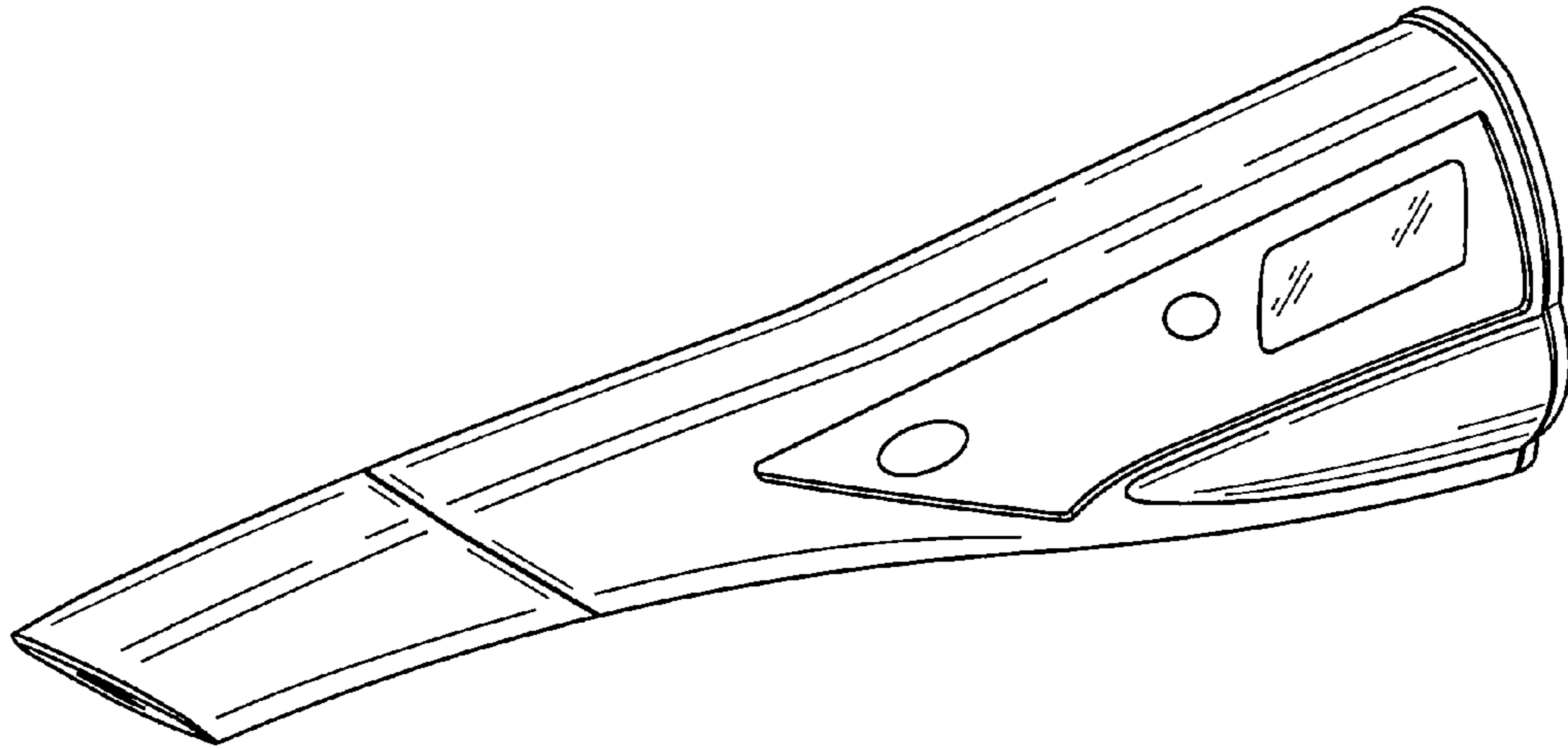


FIG. 1

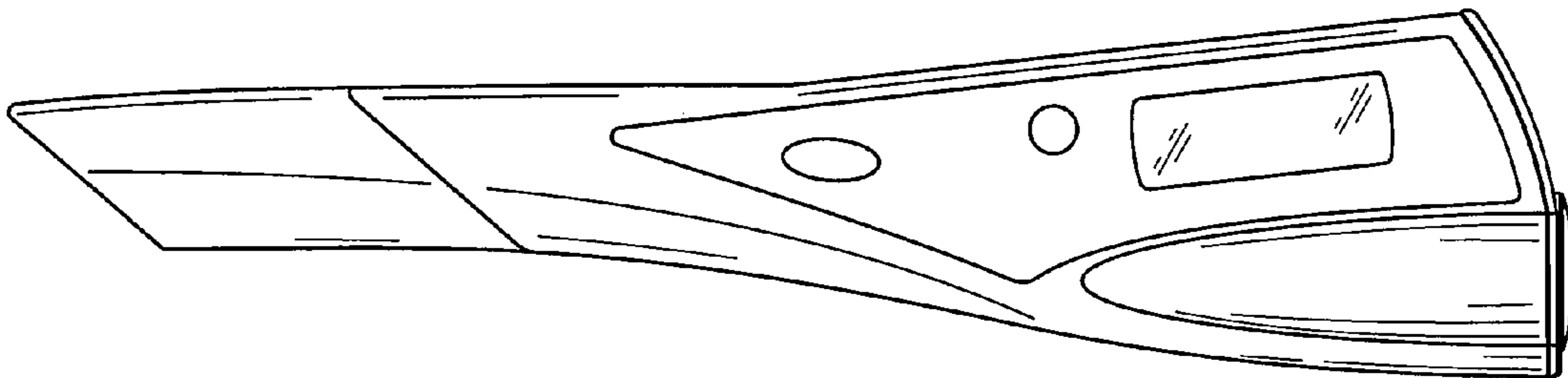


FIG. 2

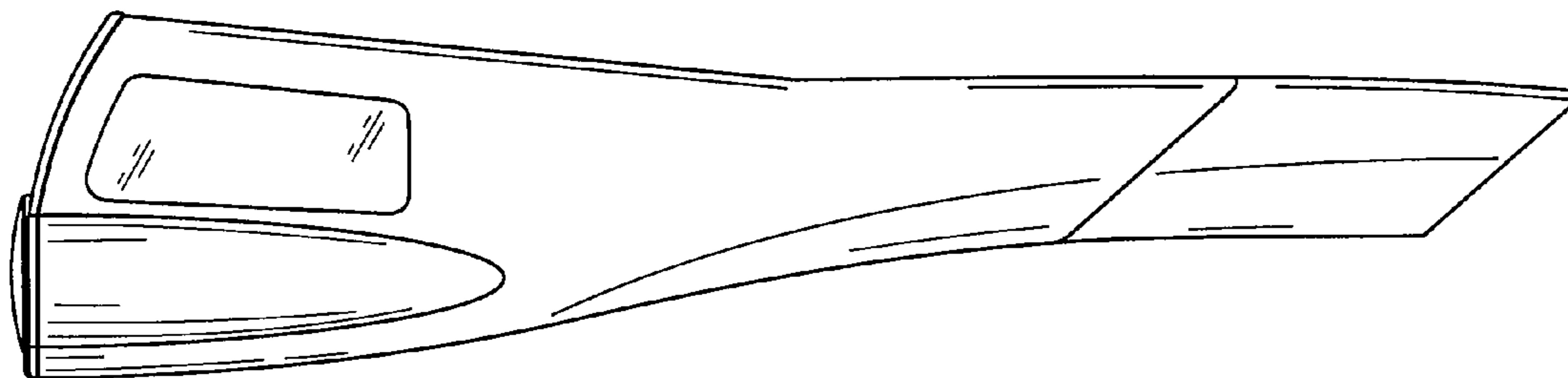


FIG. 3

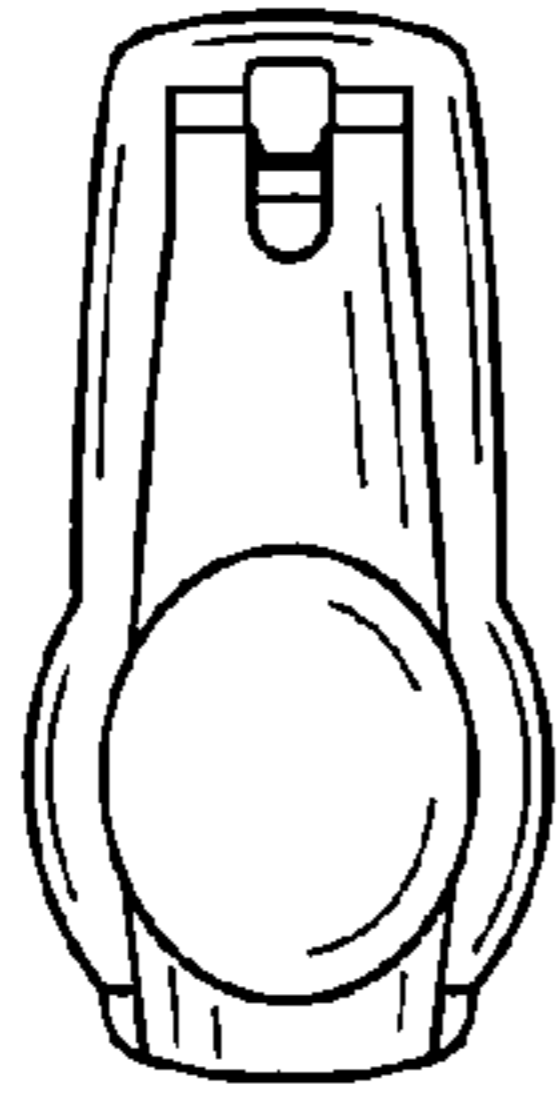


FIG. 4

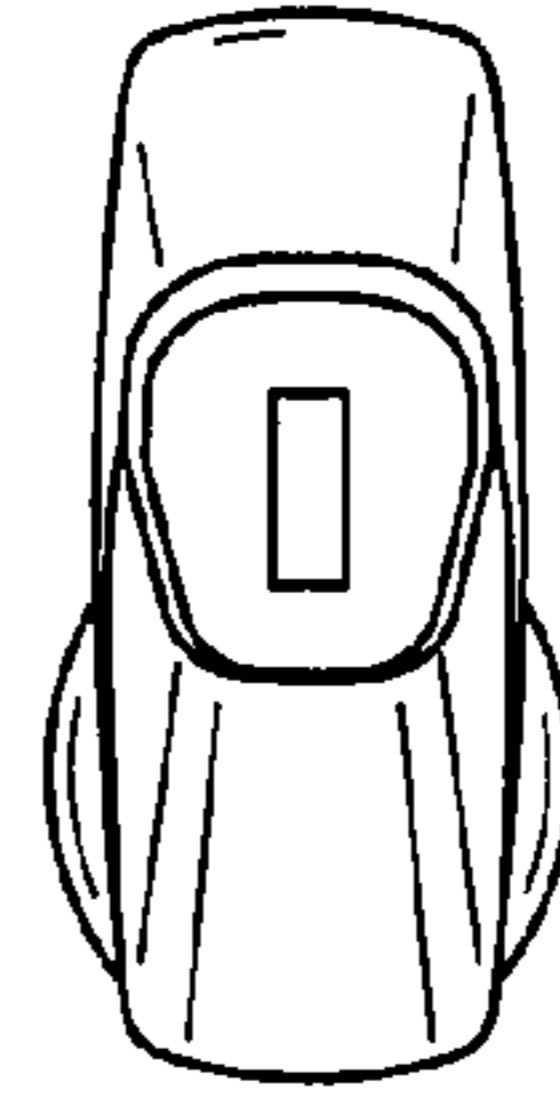


FIG. 5

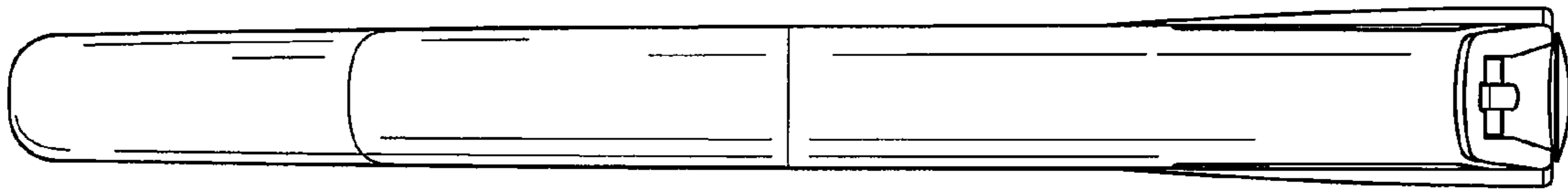


FIG. 6

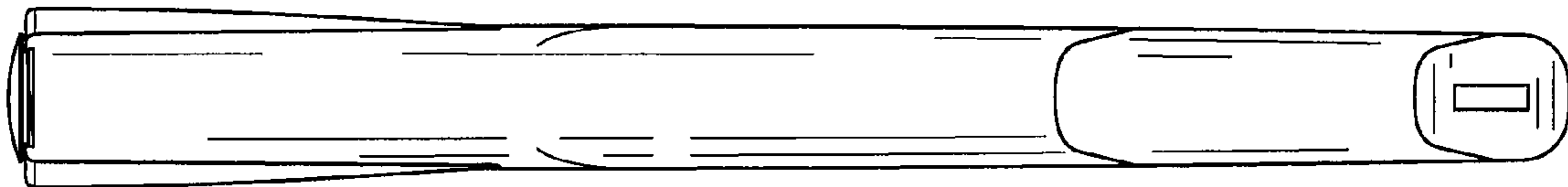


FIG. 7